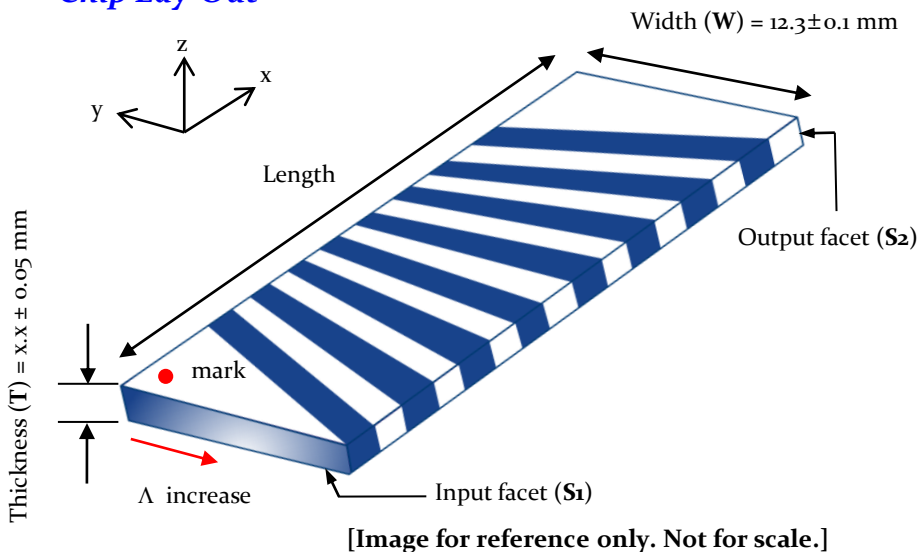


- Chip Lay-Out



Items	Properties	Inspection
Material	5 mol.% MgO:LN	NA
Period (Λ, μm)	20.50~23.50	Microscope
Main Function	Difference Frequency Generation	NA
Parallelism/Perpendicularity	≤5'/21'	Autocollimator
Flatness	≤λ/6 (λ=633nm)	Interferometer
Scratch/Dig	≤20/10	Microscope
Optical coating (S ₁ /S ₂ facets)	Si/S ₂ @730~870(R<0.5%) /1064(R<0.5%) /2300~4800(R<5%) nm	Spectral Analyzer
Aperture Size	12.3 x 1.0 mm ² (W x T)	Cutting Machine
Available Length	10/25/50 ± 0.2 mm	
Clear Aperture *	≥80% (T), ≥ 10.9 mm (W) * ₁	NA

*₁ Poled fan-out grating width =10.9mm

- Phase Matching Tuning Curve

